

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination OHSHIMA ET AL.	
		Examiner Sang H Nguyen	Art Unit 2877	Page 1 of 1

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	B	US-6,411,377 /	06-2002	Noguchi et al.	356/237.4
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**NON-PATENT DOCUMENTS**

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